

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3662	skin adj effect	USPAT	OR	ON	2005/08/19 11:44
L2	40	(skin adj effect).ti.	USPAT	OR	ON	2005/08/19 11:41
L3	3662	1 and (skin adj effect)	USPAT	OR	ON	2005/08/19 11:41
L4	40	2 and (skin adj effect)	USPAT	OR	ON	2005/08/19 11:41
L5	4	(skin adj effect) with frequency with calculate	USPAT	OR	ON	2005/08/19 11:50
L6	1645	(skin adj effect) with frequency	USPAT	OR	ON	2005/08/19 11:57
L7	339	(skin adj effect) with depth	USPAT	OR	ON	2005/08/19 11:57
L8	173	(skin adj effect) with depth with frequency	USPAT	OR	ON	2005/08/19 11:59
L9	173	8 and (skin adj effect) and depth and frequency	USPAT	OR	ON	2005/08/19 12:00
L10	61	9 and equation	USPAT	OR	ON	2005/08/19 11:59
L11	4	(skin adj effect) with depth with frequency with equation	USPAT	OR	ON	2005/08/19 11:59
L12	61	10 and (skin adj effect) and depth and frequency and equation	USPAT	OR	ON	2005/08/19 12:01
L13	4	11 and (skin adj effect) and depth and frequency and equation	USPAT	OR	ON	2005/08/19 12:09
L14	144	(resistance adj3 conductor) with (skin adj effect)	USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/19 12:19

L15	144	14 and (resistance adj3 conductor) and (skin adj effect)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:17
L16	90	15 and (model or simulate or simulation or simulating or modeling)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:18
L17	4	((resistance adj3 conductor) with (skin adj effect)) same (model or modeled or simulate or simulated or simulating)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:22
L18	82	(model or modeling or simulate or simulating or simulated) with (skin adj effect)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:23
L19	75	18 and (model or modeling or simulate or simulating or simulated) and (skin adj effect) and (conductor or segment or depth or frequency or resistance or element)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:28
L20	24	19 and depth	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:49

L21	12	(skin adj effect) with depth with (model or modeling or segment or element or simulate or simulation)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:53
L22	12	21 and (skin adj effect) and depth and (model or modeling or segment or element or simulate or simulation)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:51
L23	12	(skin adj effect) with depth with (model or modeling or segment or element or simulate or simulation or calculate)	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:54
L24	0	(skin adj effect) with depth with calculate	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:54
L25	0	(skin adj effect) with depth with estimate	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:55
L26	18	((skin adj effect) and model).ti,ab.	USPAT; EPO; JPO; DERWEN T; IBM_TD B	OR	ON	2005/08/19 12:58
L27	1547	(703/2,14,5).CCLS.	USPAT	OR	OFF	2005/08/19 12:58

L28	12	27 and (skin adj effect)	USPAT	OR	ON	2005/08/19 13:10
L29	2	(skin adj effect) same (finite adj element)	USPAT	OR	ON	2005/08/19 13:14
L30	1	conductor with model with (segment or element) with divide	USPAT	OR	ON	2005/08/19 13:15
L31	89	conductor with model with (segment or element)	USPAT	OR	ON	2005/08/19 13:15
L32	88	31 not 30	USPAT	OR	ON	2005/08/19 13:16
L33	25	(skin adj effect) with geometry	USPAT	OR	ON	2005/08/19 13:20
L34	347	(skin adj effect) same (element or segment)	USPAT	OR	ON	2005/08/19 13:21